Contents:

H-field probe	SX-R 3-1
H-field probe	SX-B 3-1
E-field probe	SX-E 03
Cable	SMA-SMA
Case	175x140x32 mm
Instructions	

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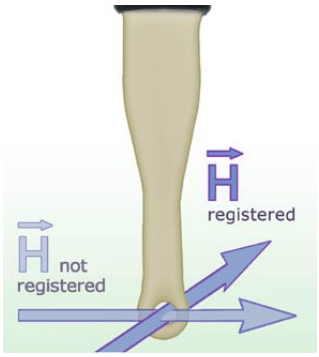
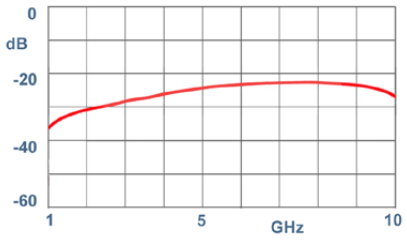
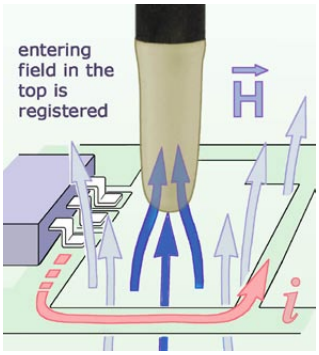
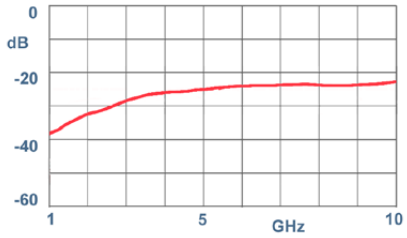
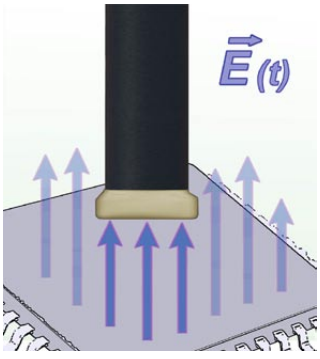
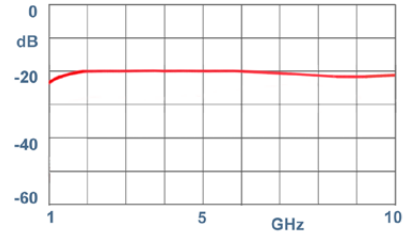
Instructions

The near field probes type SX enable the measurement of high-frequency near fields of electronic modules, components and IC pins.
The probes have electrically shielded probe heads which have been developed especially for the upper limit frequencies in the 10 GHz range. These passive probes have no pre-amplifier and are connected to the 50 Ohm input of a spectrum analyser via a cable with a SMA connector.

NEAR FIELD PROBES type SX FREQUENCY RANGE 1 GHz to 10 GHz

Application	Description	Characteristic
	**SX-R 3-1** The near field probe is designed for the detection of HF magnetic fields with a high geometrical resolution. The field orientation and distribution can be detected by moving the probe around conductor runs, bypass capacitors, EMC components and within IC pin and supply system areas. **Frequenzy range: 1 GHz to 10 GHz** **Resolution approx. < 1 mm**	
	**SX-B 3-1** The near field probe is designed for the detection of magnetic fields which are emitted vertically from the surface of PCBs and is thus ideal for investigating current loops. The probe allows the measurement in confined board areas (between large controller components, for example). **Frequenzy range: 1 GHz to 10 GHz** **Diameter approx. 4 mm** **Resolution approx. < 2 mm**	
	**SX-E 03** The near field probe is designed for the analysis of E field coupling out, detection of coupling mechanisms on modules and evaluation of switching edges on signal leads. **Frequenzy range: 1 GHz to 10 GHz** **Electrode surface area:** **approx. 4 x 4 mm**	

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